

EAST Search History

S34	216	(700/112).CCLS.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2006/10/24 19:51
S35	1306	(700/28).CCLS.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2006/10/24 19:51
S36	382	(712/300).CCLS.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2006/10/24 19:51
S37	888	(700/97).CCLS.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2006/10/24 19:51
S38	1729	(718/100).CCLS.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2006/10/24 19:52
S39	1350	(718/102).CCLS.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2006/10/24 19:52
S41	3234654	(ELECTRO ADJ5 STATIC) OR (ELECTRICAL NEAR OVERSTRESS) OR LATCH ADJ3 UP OR ((ELECTRON OR ELECTRICAL) NEAR DATA OR INFORMATION) OR CONTAMINATION OR NEGATIVE ADJ BIAS	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/10/24 19:56
S42	0	((ELECTRO ADJ5 STATIC) OR (ELECTRICAL NEAR OVERSTRESS) OR LATCH ADJ3 UP OR ((ELECTRON OR ELECTRICAL) NEAR DATA OR INFORMATION) OR CONTAMINATION OR (NEGATIVE ADJ BIAS)) AND SCHEDULE SAME OPTIMIZE6	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/10/24 19:57

EAST Search History

S43	3853	((ELECTRO ADJ5 STATIC) OR (ELECTRICAL NEAR OVERSTRESS) OR LATCH ADJ3 UP OR ((ELECTRON OR ELECTRICAL) NEAR DATA OR INFORMATION) OR CONTAMINATION OR (NEGATIVE ADJ BIAS)) AND SCHEDULE SAME OPTIMIZ\$6	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/10/24 19:57
S44	2280	((ELECTRO ADJ5 STATIC) OR (ELECTRICAL NEAR OVERSTRESS) OR LATCH ADJ3 UP OR ((ELECTRON OR ELECTRICAL) NEAR DATA OR INFORMATION) OR CONTAMINATION OR (NEGATIVE ADJ BIAS)) AND SCHEDULE SAME OPTIMIZ\$6 AND MODEL	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/10/24 19:57
S45	828	((ELECTRO ADJ5 STATIC) OR (ELECTRICAL NEAR OVERSTRESS) OR LATCH ADJ3 UP OR ((ELECTRON OR ELECTRICAL) NEAR DATA OR INFORMATION) OR CONTAMINATION OR (NEGATIVE ADJ BIAS)) AND SCHEDULE SAME OPTIMIZ\$6 AND (MODEL OR ALGORITHM) AND REAL ADJ TIME AND PRIORIT\$5	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/10/24 19:58
S46	139	((ELECTRO ADJ5 STATIC) OR (ELECTRICAL NEAR OVERSTRESS) OR LATCH ADJ3 UP OR ((ELECTRON OR ELECTRICAL) NEAR DATA OR INFORMATION) OR CONTAMINATION OR (NEGATIVE ADJ BIAS)) AND SCHEDULE SAME OPTIMIZ\$6 AND (MODEL OR ALGORITHM) AND REAL ADJ TIME AND PRIORIT\$5 AND MASK	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/10/24 20:14
S47	0	((ELECTRO ADJ5 STATIC) OR (ELECTRICAL NEAR OVERSTRESS) OR LATCH ADJ3 UP OR ((ELECTRON OR ELECTRICAL) NEAR DATA OR INFORMATION) OR CONTAMINATION OR (NEGATIVE ADJ BIAS)) AND SCHEDULE SAME OPTIMIZ\$6 AND (MODEL OR ALGORITHM) AND REAL ADJ TIME AND PRIORIT\$5 AND MASK AND RERELIABILITY	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/10/24 19:59

EAST Search History

S48	0	((ELECTRO ADJ5 STATIC) OR (ELECTRICAL NEAR OVERSTRESS) OR LATCH ADJ3 UP OR ((ELECTRON OR ELECTRICAL) NEAR DATA OR INFORMATION) OR CONTAMINATION OR (NEGATIVE ADJ BIAS)) AND SCHEDULE SAME OPTIMIZ\$6 AND (MODEL OR ALGORITHM) AND REAL ADJ TIME AND PRIORIT\$5 AND MASK AND RELIABILITY	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/10/24 20:00
S49	2837	((ELECTRO ADJ5 STATIC) OR (ELECTRICAL NEAR OVERSTRESS) OR LATCH ADJ3 UP OR ((ELECTRON OR ELECTRICAL) NEAR DATA OR INFORMATION) OR CONTAMINATION OR (NEGATIVE ADJ BIAS)) AND SCHEDULE SAME OPTIMIZ\$6 AND (MODEL OR ALGORITHM) not S46	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/10/24 20:15
S51	792	((ELECTRO ADJ5 STATIC) OR (ELECTRICAL NEAR OVERSTRESS) OR LATCH ADJ3 UP OR ((ELECTRON OR ELECTRICAL) NEAR DATA OR INFORMATION) OR CONTAMINATION OR (NEGATIVE ADJ BIAS)) same SCHEDULE SAME OPTIMIZ\$6 AND (MODEL OR ALGORITHM) not S46	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/10/24 20:15
S52	115	((ELECTRO ADJ5 STATIC) OR (ELECTRICAL NEAR OVERSTRESS) OR LATCH ADJ3 UP OR ((ELECTRON OR ELECTRICAL) NEAR DATA OR INFORMATION) OR CONTAMINATION OR (NEGATIVE ADJ BIAS)) same SCHEDULE SAME OPTIMIZ\$6 AND (MODEL OR ALGORITHM) not S46 and "700"/\$.ccls.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/10/24 20:18
S53	2	((ELECTRO ADJ5 STATIC) OR (ELECTRICAL NEAR OVERSTRESS) OR LATCH ADJ3 UP OR ((ELECTRON OR ELECTRICAL) NEAR (DATA OR INFORMATION)) OR CONTAMINATION OR (NEGATIVE ADJ BIAS)) same SCHEDULE SAME OPTIMIZ\$6 AND (MODEL OR ALGORITHM) not S46 and "700"/\$.ccls.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/10/24 20:20

EAST Search History

S54	24	((ELECTRO ADJ5 STATIC) OR (ELECTRICAL NEAR OVERSTRESS) OR LATCH ADJ3 UP OR ((ELECTRON OR ELECTRICAL) NEAR (DATA OR INFORMATION)) OR CONTAMINATION OR (NEGATIVE ADJ BIAS)) and SCHEDULE SAME OPTIMIZ\$6 AND (MODEL OR ALGORITHM) not S46 and "700"/\$.ccls.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/10/24 20:21
S55	492	esd near sensitiv\$5	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/12/11 15:14
S56	3	esd near sensitiv\$5 and schedule	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/12/11 15:14
S57	36137	sensitiv\$5 and schedule	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/12/11 15:15
S58	16906	sensitivities and schedule	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/12/11 15:16
S59	773	sensitivities same schedule	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/12/11 15:16
S60	773	(sensitivies or sensitivity) same schedule	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/12/11 15:17

EAST Search History

S61	2	(sensitivies or sensitivity) same floor near schedule	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/12/11 15:19
S62	343	(sensitivies or sensitivity) same schedule and model	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/12/11 15:20
S63	118	(sensitivies or sensitivity) same (schedul\$4) and model and assembly	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/12/11 15:22
S64	0	(sensitivies or sensitivity) same (schedul\$4) and model and assembly and ("700"/\$.clas. or "718"/\$.clas. or "712"/\$.clas.)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/12/11 15:23
S65	5	SCHEDULE SAME OPTIMIZ\$6 AND SEMI ADJ6 CONDUCTOR AND SENSITIV\$6 and emission	US-PGPUB; USPAT	OR	ON	2006/12/11 15:27
S66	428	(700/99).CCLS.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2006/12/11 15:43
S67	399	(702/81).CCLS.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2006/12/11 15:36
S68	463	(702/84).CCLS.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2006/12/11 15:36
S69	0	("((emission)with(monitor\$3ordetec t\$3))andschedule").PN.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2006/12/11 15:44

EAST Search History

S70	2074	((emission) with (monitor\$3 or detect\$3)) and schedule	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/12/11 15:44
S74	53564	("205").CLAS.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2006/12/11 15:46
S75	146416	("324").CLAS.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2006/12/11 15:46
S76	81	(emission) and schedule and (S74 or S75)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/12/11 15:46
S77	568	(718/103).CCLS.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2006/12/11 15:49
S78	548	(700/100).CCLS.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2006/12/11 15:51
S79	166	(700/101).CCLS.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2006/12/11 15:51
S80	111	(700/102).CCLS.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2006/12/11 15:51

EAST Search History

S81	93	(700/105).CCLS.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2006/12/11 15:51
S82	779	(700/108).CCLS.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2006/12/11 15:51
S83	378	(700/109).CCLS.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2006/12/11 15:51
S84	218	(700/112).CCLS.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2006/12/11 15:51
S85	1314	(700/28).CCLS.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2006/12/11 15:51
S86	387	(712/300).CCLS.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2006/12/11 15:51
S87	909	(700/97).CCLS.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2006/12/11 15:51
S88	1760	(718/100).CCLS.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2006/12/11 15:51

EAST Search History

S89	1375	(718/102).CCLS.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2006/12/11 15:51
S90	8364	S66 or S67 or S68 or S77 or S78 or S79 or S80 or S81 or S82 or S83 or S84 or S85 or S86 or S87 or S88 or S89	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/12/11 15:51
S91	291	S90 and (schedule or path) and (sensitivities or sensitivity or (electrostatic near3 discharge) or overstress or (latch near2 up) or electron or (ion near2 contamination) or (negative near bias))	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/12/11 15:57
S92	151	S90 and (optimal or optimization) with schedule	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/12/11 16:48
S93	1	10/710065	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/12/11 16:48
S94	5363	(radiation or emission or (flash near2 tube) or tube) same (schedule or plann or planning or scheduling)	US-PGPUB; USPAT	OR	ON	2006/12/12 10:43
S95	1657	(radiation or emission or (flash near2 tube) or tube) same (schedule or plann or planning or scheduling) and (optimal or optimization)	US-PGPUB; USPAT	OR	ON	2006/12/12 10:43
S96	997	(radiation or emission or (flash near2 tube) or tube) same (schedule or plann or planning or scheduling) and (optimal or optimization) and model	US-PGPUB; USPAT	OR	ON	2006/12/12 10:43

EAST Search History

S98	951	(radiation or emission or (flash near2 tube) or tube) same (schedule or plann or planning or scheduling) and (optimal or optimization) and model and (testing or test or analyse or check or examine or experiment or inspect or inspection or measure or sample or trial or verify or analyze)	US-PGPUB; USPAT	OR	ON	2006/12/12 10:46
S99	1488	(radiation or emission or (flash near2 tube) or tube) same (schedule or plan or planning or scheduling) and (optimal or optimization) and model and (testing or test or analyse or check or examine or experiment or inspect or inspection or measure or sample or trial or verify or analyze)	US-PGPUB; USPAT	OR	ON	2006/12/12 10:47
S10 0	188	(radiation or emission or (flash near2 tube) or tube) same (schedule or plan or planning or scheduling) same (optimal or optimization) and model and (testing or test or analyse or check or examine or experiment or inspect or inspection or measure or sample or trial or verify or analyze)	US-PGPUB; USPAT	OR	ON	2006/12/12 10:47
S10 1	12	(radiation or emission or (flash near2 tube) or tube) same (schedule or plan or planning or scheduling) same (optimal or optimization) and model and (testing or test or analyse or check or examine or experiment or inspect or inspection or measure or sample or trial or verify or analyze) and (wafer or semiconductor or rectile)	US-PGPUB; USPAT	OR	ON	2006/12/12 10:49
S10 2	428	(700/99).CCLS.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2006/12/12 10:49
S10 3	400	(702/81).CCLS.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2006/12/12 10:49

EAST Search History

S10 4	463	(702/84).CCLS.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2006/12/12 10:49
S10 5	572	(718/103).CCLS.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2006/12/12 10:49
S10 6	548	(700/100).CCLS.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2006/12/12 10:49
S10 7	166	(700/101).CCLS.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2006/12/12 10:49
S10 8	111	(700/102).CCLS.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2006/12/12 10:49
S10 9	93	(700/105).CCLS.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2006/12/12 10:49
S11 0	781	(700/108).CCLS.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2006/12/12 10:49
S11 1	378	(700/109).CCLS.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2006/12/12 10:49

EAST Search History

S11 2	218	(700/112).CCLS.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2006/12/12 10:49
S11 3	1317	(700/28).CCLS.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2006/12/12 10:49
S11 4	387	(712/300).CCLS.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2006/12/12 10:49
S11 5	912	(700/97).CCLS.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2006/12/12 10:49
S11 6	1764	(718/100).CCLS.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2006/12/12 10:49
S11 7	1381	(718/102).CCLS.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2006/12/12 10:49
S11 8	8380	S102 or S103 or S104 or S105 or S106 or S107 or S108 or S109 or S110 or S111 or S112 or S113 or S114 or S115 or S116 or S117	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/12/12 10:49

EAST Search History

S11 9	5	(radiation or emission or (flash near2 tube) or tube) same (schedule or plan or planning or scheduling) and (optimal or optimization) and model and (testing or test or analyse or check or examine or experiment or inspect or inspection or measure or sample or trial or verify or analyze) and (wafer or semiconductor or rectile) and S118	US-PGPUB; USPAT	OR	ON	2006/12/12 13:21
S12 0	86	(schedule or plan or planning or scheduling) same (optimal or optimization) and model and (testing or test or analyse or check or examine or experiment or inspect or inspection or measure or sample or trial or verify or analyze) and (wafer or semiconductor or rectile) and S118	US-PGPUB; USPAT	OR	ON	2006/12/12 14:38
S12 1	1	floor near (schedule or plan or planning or scheduling) same (optimal or optimization) and model and (testing or test or analyse or check or examine or experiment or inspect or inspection or measure or sample or trial or verify or analyze) and (wafer or semiconductor or rectile) and S118	US-PGPUB; USPAT	OR	ON	2006/12/12 10:58

EAST Search History

Ref #	Hits	Search Query	DBs	Default Operator	Plurals	Time Stamp
S1	913	(700/97).CCLS.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2006/12/14 09:40
S2	428	(700/99).CCLS.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2006/12/14 09:40
S3	549	(700/100).CCLS.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2006/12/14 09:41
S4	166	(700/101).CCLS.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2006/12/14 09:41
S5	111	(700/102).CCLS.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2006/12/14 09:41
S6	243	(700/103).CCLS.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2006/12/14 09:41
S7	93	(700/105).CCLS.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2006/12/14 11:50
S8	783	(700/108).CCLS.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2006/12/14 11:55

EAST Search History

S9	378	(700/109).CCLS.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2006/12/14 09:41
S10	218	(700/112).CCLS.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2006/12/14 09:41
S11	1725	(700/121).CCLS.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2006/12/14 11:20
S12	165	(700/128).CCLS.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2006/12/14 09:41
S13	224	(700/174).CCLS.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2006/12/14 09:41
S14	774	(700/175).CCLS.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2006/12/14 09:41
S16	515	(700/178).CCLS.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2006/12/14 09:44
S17	162	(700/177).CCLS.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2006/12/14 09:44

EAST Search History

S18	1922	automated near2 handling near2 system	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/12/14 11:21
S19	60	(automated near2 handling near2 system) same (scheduling\$4 or planner or optimization\$5)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/12/14 11:47
S20	76	(automated near2 handling near2 system or amhs) same (scheduling\$4 or planner or optimization\$5)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/12/14 11:26
S21	76	((automated near2 handling near2 system) or amhs) same (scheduling\$4 or planner or optimization\$5)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/12/14 11:27
S22	16	((automated near2 handling near2 system) or amhs) same (scheduling\$4 or planner or optimization\$5) not S19	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/12/14 11:28
S23	191	(700/21).CCLS.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2006/12/14 11:50
S24	633	(700/95).CCLS.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2006/12/14 11:50
S25	1319	(700/28).CCLS.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2006/12/14 11:55

EAST Search History

S26	4030	(438/17).CCLS.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2006/12/14 11:55
S27	2314	(438/14).CCLS.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2006/12/14 11:55
S28	483	(438/5).CCLS.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2006/12/14 11:55
S29	711	(438/10).CCLS.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2006/12/14 11:55
S30	162	(438/11).CCLS.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2006/12/14 11:55
S31	148	(714/100).CCLS.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2006/12/14 11:55
S32	1155	(714/47).CCLS.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2006/12/14 11:55
S33	1043	(714/48).CCLS.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2006/12/14 11:55

EAST Search History

S34	463	(702/84).CCLS.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2006/12/14 11:56
S35	402	(702/81).CCLS.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2006/12/14 11:56
S36	187	(702/40).CCLS.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2006/12/14 11:56
S37	1593	(702/182).CCLS.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2006/12/14 11:56
S38	426	(718/101).CCLS.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2006/12/14 11:56
S39	1381	(718/102).CCLS.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2006/12/14 11:56
S40	573	(718/103).CCLS.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2006/12/14 11:56
S41	302	(250/586).CCLS.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2006/12/14 11:56

EAST Search History

S42	132	(324/408).CCLS.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2006/12/14 11:56
S43	150	(324/409).CCLS.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2006/12/14 11:56
S44	500	(324/719).CCLS.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2006/12/14 11:57
S45	748	(324/500).CCLS.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2006/12/14 11:57
S46	443	(340/657).CCLS.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2006/12/14 11:57
S47	22787	S1 S2 S3 S4 S5 S6 S9 S10 S12 S13 S14 S16 S17 S11 S23 S24 S7 S8 S25 S26 S27 S28 S29 S30 S31 S32 S33 S34 S35 S36 S37 S38 S39 S40 S41 S42 S43 S44 S45 S46	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/12/14 14:40
S59	378	(700/109).CCLS.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2006/12/14 14:22
S60	148	(714/100).CCLS.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2006/12/14 14:32

EAST Search History

S61	483	(438/5).CCLS.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2006/12/14 14:32
S63	1155	(714/47).CCLS.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2006/12/14 14:33
S64	913	(700/97).CCLS.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2006/12/14 14:43
S65	428	(700/99).CCLS.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2006/12/14 14:43
S66	549	(700/100).CCLS.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2006/12/14 14:43
S67	166	(700/101).CCLS.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2006/12/14 14:43
S68	111	(700/102).CCLS.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2006/12/14 14:43
S69	243	(700/103).CCLS.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2006/12/14 14:43

EAST Search History

S70	93	(700/105).CCLS.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2006/12/14 14:43
S71	783	(700/108).CCLS.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2006/12/14 14:43
S72	378	(700/109).CCLS.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2006/12/14 14:43
S73	218	(700/112).CCLS.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2006/12/14 14:43
S74	1725	(700/121).CCLS.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2006/12/14 14:43
S75	165	(700/128).CCLS.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2006/12/14 14:43
S76	224	(700/174).CCLS.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2006/12/14 14:43
S77	774	(700/175).CCLS.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2006/12/14 14:43

EAST Search History

S78	515	(700/178).CCLS.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2006/12/14 14:43
S79	162	(700/177).CCLS.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2006/12/14 14:43
S80	191	(700/21).CCLS.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2006/12/14 14:43
S81	633	(700/95).CCLS.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2006/12/14 14:43
S82	1319	(700/28).CCLS.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2006/12/14 14:43
S83	4030	(438/17).CCLS.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2006/12/14 14:43
S84	2314	(438/14).CCLS.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2006/12/14 14:43
S85	483	(438/5).CCLS.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2006/12/14 14:43

EAST Search History

S86	711	(438/10).CCLS.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2006/12/14 14:43
S87	162	(438/11).CCLS.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2006/12/14 14:43
S88	148	(714/100).CCLS.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2006/12/14 14:43
S89	1155	(714/47).CCLS.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2006/12/14 14:43
S90	1043	(714/48).CCLS.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2006/12/14 14:43
S91	463	(702/84).CCLS.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2006/12/14 14:43
S92	402	(702/81).CCLS.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2006/12/14 14:43
S93	187	(702/40).CCLS.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2006/12/14 14:43

EAST Search History

S94	1593	(702/182).CCLS.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2006/12/14 14:43
S95	426	(718/101).CCLS.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2006/12/14 14:43
S96	1381	(718/102).CCLS.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2006/12/14 14:43
S97	573	(718/103).CCLS.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2006/12/14 14:43
S98	302	(250/586).CCLS.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2006/12/14 14:43
S99	132	(324/408).CCLS.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2006/12/14 14:43
S10 0	150	(324/409).CCLS.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2006/12/14 14:43
S10 1	500	(324/719).CCLS.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2006/12/14 14:43

EAST Search History

S10 2	748	(324/500).CCLS.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2006/12/14 14:43
S10 3	443	(340/657).CCLS.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2006/12/14 14:43
S10 4	22787	S64 S65 S66 S67 S68 S69 S72 S73 S75 S76 S77 S78 S79 S74 S80 S81 S70 S71 S82 S83 S84 S85 S86 S87 S88 S89 S90 S91 S92 S93 S94 S95 S96 S97 S98 S99 S100 S101 S102 S103	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/12/14 14:43
S10 5	1706	S104 and ((planning or planner or plan\$5 or scheduling or schedule) same (testing or test or analyse or analyze or check or examine or experiment or inspect or inspection or measur\$3 or sample or sampling or trial or verify)) and (wafer or semiconductor or rectile)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/12/14 14:45
S10 7	106	S104 and ((planning or planner or plan\$5 or scheduling or schedule) same (testing or test or analyse or analyze or check or examine or experiment or inspect or inspection or measur\$3 or sample or sampling or trial or verify)) same (emission or radiation or sensitivit\$5 or tube) and (wafer or semiconductor or rectile)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/12/14 14:49
S10 8	106	S104 and ((planning or planner or plan\$5 or scheduling or schedule) same (testing or test or analyse or analyze or check or examine or experiment or inspect or inspection or measur\$3 or sample or sampling or trial or verify)) same (emission or radiation or sensitivit\$5 or tube) and (wafer or semiconductor or rectile)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/12/14 14:46

EAST Search History

S10 9	302	S104 and ((planning or planner or plan\$5 or scheduling or schedule) same (testing or test or analyse or analyze or check or examine or experiment or inspect or inspection or measur\$3 or sample or sampling or trial or verify)) same (emission or radiation or sensitivit\$5 or tube or electrical) and (wafer or semiconductor or rectile)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/12/14 14:50
S11 0	136	S104 and ((planning or planner or plan\$5 or scheduling or schedule) same (testing or test or analyse or analyze or check or examine or experiment or inspect or inspection or measur\$3 or sample or sampling or trial or verify)) same (emission or radiation or sensitivit\$5 or tube or electrical near (proport\$4 or characteristic\$2)) and (wafer or semiconductor or rectile)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/12/14 15:05
S11 1	210	S104 and ((planning or planner or plan\$5 or scheduling or schedule) and (testing or test or analyse or analyze or check or examine or experiment or inspect or inspection or measur\$3 or sample or sampling or trial or verify)) same (emission or radiation or sensitivit\$5 or tube or electrical near (proport\$4 or characteristic\$2)) and (wafer or semiconductor or rectile)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/12/14 15:12
S11 2	1565	S104 and ((planning or planner or plan\$5 or scheduling or schedule) and (testing or test or analyse or analyze or check or examine or experiment or inspect or inspection or measur\$3 or sample or sampling or trial or verify)) and (emission or radiation or sensitivit\$5 or tube or electrical near (proport\$4 or characteristic\$2)) and (wafer or semiconductor or rectile)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/12/14 15:13

EAST Search History

S11 3	77	S104 and ((planning or planner or plan\$5 or scheduling or schedule) and (testing or test or analyse or analyze or check or examine or experiment or inspect or inspection or measur\$3 or sample or sampling or trial or verify)) with (emission or radiation or sensitivit\$5 or tube or electrical near (propert\$4 or characteristic\$2)) and (wafer or semiconductor or rectile)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/12/14 15:22
S11 4	36	S104 and ((planning or planner or plan\$5 or scheduling or schedule) and (testing or test or analyse or analyze or check or examine or experiment or inspect or inspection or measur\$3 or sample or sampling or trial or verify)) with (emission or radiation or sensitivit\$5 or tube or electrical near (propert\$4 or characteristic\$2)) and (wafer or semiconductor or rectile) and (optimal or optimiz\$6 or optimis\$5)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/12/14 15:24
S11 5	601	S104 and ((planning or planner or plan\$5 or scheduling or schedule) and (testing or test or analyse or analyze or check or examine or experiment or inspect or inspection or measur\$3 or sample or sampling or trial or verify)) and (emission or radiation or sensitivit\$5 or tube or electrical near (propert\$4 or characteristic\$2)) and (wafer or semiconductor or rectile) and (optimal or optimiz\$6 or optimis\$5)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/12/14 15:23
S11 6	1396	(718/102).CCLS.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2007/01/06 12:25

EAST Search History

S11 7	198	(US-20050283265-\$ or US-20030067253-\$ or US-20060007434-\$ or US-20010018325-\$ or US-20020032993-\$ or US-20050093277-\$ or US-20020030954-\$ or US-20020064007-\$ or US-20020073785-\$ or US-20030098772-\$ or US-20040018388-\$ or US-20040056754-\$ or US-20040082083-\$ or US-20040156538-\$ or US-20050188769-\$ or US-20050212097-\$ or US-20050221594-\$ or US-20060219030-\$ or US-20060220092-\$ or US-20060261819-\$).did. or (US-4937877-\$ or US-5359319-\$ or US-5461369-\$ or US-5463379-\$ or US-6972933-\$ or US-6084759-\$ or US-5234104-\$ or US-6398324-\$ or US-4982333-\$ or US-5670946-\$ or US-5959806-\$ or US-6002552-\$ or US-6137622-\$ or US-6181459-\$ or US-5412911-\$ or US-4411113-\$ or US-4541130-\$ or US-4827901-\$ or US-4863217-\$ or US-4919123-\$ or US-5255197-\$ or US-5444632-\$ or US-5464236-\$ or US-5465456-\$ or US-5509722-\$ or US-5577362-\$). did. or (US-5588791-\$ or US-5597139-\$ or US-5775642-\$ or US-6104970-\$ or US-6311434-\$ or US-6474027-\$ or US-4307329-\$ or US-6163915-\$ or US-4261379-\$ or US-4473960-\$ or US-4625115-\$ or US-4761557-\$ or US-4813498-\$ or US-4867418-\$ or US-4886395-\$ or US-5323656-\$ or US-5344523-\$ or US-5374796-\$ or US-5469058-\$ or US-5646594-\$ or US-5816256-\$ or US-5937578-\$ or US-6202824-\$ or US-6216727-\$ or US-7143658-\$ or US-5652155-\$ or US-5814864-\$). did. or (US-5990499-\$ or US-4855620-\$ or US-4864454-\$ or US-4866425-\$ or US-4895620-\$ or US-4935839-\$ or US-4970625-\$ or US-5060037-\$ or US-5223737-\$ or US-5497163-\$ or US-5523699-\$ or US-5541053-\$ or US-5565698-\$ or US-5567579-\$ or US-5571737-\$ or US-5604693-\$ or US-5604438-\$ or US-5682008-\$ or US-5717560-\$ or US-5781377-\$ or US-5790448-\$ or US-5793774-\$ or US-5793083-\$ or	US-PGPUB; USPAT	OR	ON	2007/01/06 11:45
1/8/2007 8:33:02 AM C:\Documents and Settings\London My Documents\EAST\Workspaces\10710065\12-14-06.wsp Page 15						

EAST Search History

S11 9	199	(US-20050283265-\$ or US-20030220828-\$ or US-20030226433-\$ or US-20030237080-\$ or US-20050010558-\$ or US-20050182506-\$ or US-20060225061-\$ or US-20040039630-\$ or US-20030233163-\$ or US-20020007484-\$ or US-20020198757-\$ or US-20040216163-\$ or US-20060015203-\$ or US-20060101052-\$ or US-20060111871-\$ or US-20020058550-\$ or US-20020107715-\$ or US-20040030428-\$ or US-20040122721-\$ or US-20050096770-\$ or US-20060007434-\$ or US-20010018325-\$ or US-20020032993-\$ or US-20040088060-\$ or US-20050015641-\$ or US-20050065674-\$).did. or (US-20060080285-\$ or US-20030067253-\$ or US-20010049595-\$ or US-20020075803-\$ or US-20060069863-\$).did. or (US-4982333-\$ or US-5444632-\$ or US-5867711-\$ or US-5515490-\$ or US-5835776-\$ or US-5854934-\$ or US-5890134-\$ or US-5930510-\$ or US-6077313-\$ or US-6151705-\$ or US-6289505-\$ or US-6449747-\$ or US-6651247-\$ or US-6879873-\$ or US-7043323-\$ or US-7089190-\$ or US-5521926-\$ or US-5937333-\$ or US-6954676-\$ or US-5202836-\$ or US-4250483-\$ or US-4425523-\$ or US-4465420-\$ or US-4819554-\$ or US-4931944-\$ or US-5016175-\$). did. or (US-5211007-\$ or US-5263290-\$ or US-5278750-\$ or US-5305599-\$ or US-5440480-\$ or US-5457476-\$ or US-5548518-\$ or US-5568401-\$ or US-5570109-\$ or US-5625377-\$ or US-5918219-\$ or US-RE36360-\$ or US-5999533-\$ or US-6003012-\$ or US-6009406-\$ or US-6047296-\$ or US-6236396-\$ or US-6240328-\$ or US-6260190-\$ or US-6341370-\$ or US-6422296-\$ or US-6634024-\$ or US-6859768-\$ or US-6914204-\$ or US-7010373-\$ or US-4787179-\$ or US-4796194-\$). did. or (US-4827422-\$ or	US-PGPUB; USPAT	OR	ON	2007/01/06 11:51
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EAST Search History

S12 0	197	(US-20050283265-\$ or US-20030220828-\$ or US-20030226433-\$ or US-20030237080-\$ or US-20050010558-\$ or US-20050182506-\$ or US-20060225061-\$ or US-20030233163-\$ or US-20020007484-\$ or US-20020198757-\$ or US-20040216163-\$ or US-20060015203-\$ or US-20060101052-\$ or US-20060111871-\$ or US-20040039630-\$ or US-20020058550-\$ or US-20020107715-\$ or US-20040030428-\$ or US-20040122721-\$ or US-20050096770-\$ or US-20030067253-\$ or US-20010049595-\$ or US-20020075803-\$ or US-20060069863-\$ or US-20060007434-\$ or US-20010018325-\$).did. or (US-20020032993-\$ or US-20040088060-\$ or US-20050015641-\$ or US-20050065674-\$ or US-20060080285-\$ or US-20050093277-\$).did. or (US-4982333-\$ or US-5444632-\$ or US-5867711-\$ or US-5515490-\$ or US-5835776-\$ or US-5854934-\$ or US-5890134-\$ or US-5930510-\$ or US-6077313-\$ or US-6151705-\$ or US-6289505-\$ or US-6449747-\$ or US-6651247-\$ or US-6879873-\$ or US-7043323-\$ or US-7089190-\$ or US-6954676-\$ or US-5202836-\$ or US-4250483-\$ or US-4425523-\$ or US-4465420-\$ or US-4819554-\$ or US-4931944-\$ or US-5016175-\$ or US-5211007-\$ or US-5263290-\$). did. or (US-5278750-\$ or US-5305599-\$ or US-5440480-\$ or US-5457476-\$ or US-5548518-\$ or US-5568401-\$ or US-5570109-\$ or US-5625377-\$ or US-5918219-\$ or US-RE36360-\$ or US-5999533-\$ or US-6003012-\$ or US-6009406-\$ or US-6047296-\$ or US-6236396-\$ or US-6240328-\$ or US-6260190-\$ or US-6341370-\$ or US-6422296-\$ or US-6634024-\$ or US-6859768-\$ or US-6914204-\$ or US-7010373-\$ or US-5521926-\$ or US-5937333-\$ or US-4787170-\$ or US-4706104-\$)	US-PGPUB; USPAT	OR	ON	2007/01/06 11:51
1/8/2007 8:33:02 AM	C:\Documents and Settings\Jordan\My Documents\EAST\Workspaces\10710065\12-14-06.wsp					Page 17

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S13 3	2	prioritizing with testing with mask	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/01/06 17:37
S13 4	2	prioritizing near5 testing with mask	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/01/06 17:38
S13 5	2	prioritizing near5 testing same mask	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/01/06 17:38
S13 6	29	priorit\$6 near5 test\$4 same mask	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/01/06 18:30
S14 1	308	automated adj material adj handling adj system	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/01/08 03:27
S14 2	68	(automated adj material adj handling adj system) and real adj time	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/01/08 03:27
S14 3	50	(automated adj material adj handling adj system) and real adj time and (semiconductor or semi adj conductor)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/01/08 03:28
S14 6	50	(automated adj material adj handling adj system) and real adj time and (semiconductor or semi adj conductor or wafer)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/01/08 03:56

EAST Search History

Ref #	Hits	Search Query	DBs	Default Operator	Plurals	Time Stamp
S25	51	SCHEDULE SAME OPTIMIZ\$6 AND SENSITIV\$6 NOT S19 NOT S20 AND (DISCHARGE OR ELECTRICAL OR ELECTRO ADJ5 STATIC\$5 OR ESD) AND "700"/\$.CCLS.	US-PGPUB; USPAT	OR	ON	2006/10/24 19:50
S27	535	(700/100).CCLS.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2006/10/24 19:51
S28	161	(700/101).CCLS.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2006/10/24 19:51
S29	110	(700/102).CCLS.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2006/10/24 19:51
S30	235	(700/103).CCLS.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2006/10/24 19:51
S31	93	(700/105).CCLS.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2006/10/24 19:51
S32	762	(700/108).CCLS.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2006/10/24 19:51
S33	373	(700/109).CCLS.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2006/10/24 19:51